

Automated software-based in-field self-test program synthesis

Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton International journal of microelectronics and computer science 2017 / p. 57-64 : ill

Automated software-based self-test generation for microprocessors

Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton Proceedings of the 24st International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2017 : Bydgoszcz, Poland, June 19-21, 2014 2017 / p. 453-458 : ill
<https://doi.org/10.23919/MIXDES.2017.8005252>

New fault models and self-test generation for microprocessors using High-Level Decision Diagrams

Jasnetski, Artjom; Raik, Jaan; Tšertov, Anton; Ubar, Raimund-Johannes 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 251-254 : ill

Software-based self-test generation for microprocessors with high-level decision diagrams

Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton; Brik, Marina Proceedings of the Estonian Academy of Sciences 2014 / p. 48-61 : ill https://artiklid.einet.ee/record=b2665215*est <https://doi.org/10.3176/proc.2014.1.08> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Software-based self-test generation for microprocessors with high-level decision diagrams

Ubar, Raimund-Johannes; Tšertov, Anton; Jasnetski, Artjom; Brik, Marina LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

Teaching digital system test

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Kruus, Margus The 27th EAAEIE Annual Conference : June 7-9, 2017, Grenoble 2017 / [6] p